

1. (Previously presented) In a semiconductor imaging chip having a plurality of active pixel sensors arranged in an array of rows and columns, each active pixel sensor having a respective internal offset voltage output superimposed on its respective active pixel sensor output, and wherein a current row of said array has an access line shared with a reset line of a previous row of said array to form a shared access/reset line which simultaneously accesses said current row and resets said previous row, a method for canceling the internal offset voltage appearing at the output of a given active pixel sensor on said current row to form a corrected output, said method comprising:

accessing a first row of said array to obtain a first sample of said given active pixel sensor output;

storing said first sample of said given active pixel sensor output of said first row of said array;

accessing a second row of said array, said first row of said array being the previous row to said second row of said array; and thereafter,

accessing said first row of said array a second time to obtain a second sample of said given active pixel sensor output;

storing said second sample of said given active pixel sensor output of said first row of said array; and

subtracting said second sample from said first sample to form said corrected output from said given active pixel sensor.

2. (Previously presented) A method in accordance with claim 1, said method comprising:

accessing a third row of said array, said first row of said array being a predetermined number of rows previous to said third row, whereby said method sets the image exposure time of said third row.

3. (Original) A method in accordance with claim 2, wherein said step of accessing said third row of said array occurs substantially simultaneously with said step of accessing said second row of said array.

4. (Canceled)

5. (Currently amended) In a semiconductor imaging chip having a plurality of active pixel sensors arranged in an array of rows and columns, wherein a current row of said array has an access line shared with a reset line of a previous row of said array to form a shared access/reset line which simultaneously accesses said current row and resets said previous row, a method for accessing the pixel signal values of said active pixel sensors, A method in accordance with claim 4, wherein each active pixel sensor has a respective internal offset voltage output superimposed on its respective active pixel sensor output,

and said method further includes canceling the respective internal offset voltage appearing at the output of a given active pixel sensor on said current row to form a corrected output, said method further comprising:

accessing row N of said array a first time;

storing a first sample of said given active pixel sensor of row N of said array during said first time;

accessing row N+1 of said array, said row N of said array being the previous row to said row N+1 of said array;

storing a second sample of said given active pixel sensor of row N of said array during said second time; and

thereafter accessing row N of said array a second time, and

subtracting said second sample from said first sample to form said corrected output from said given active pixel sensor.

6. (Currently amended) A method in accordance with claim 45, wherein said method further includes setting the image exposure time of said semiconductor imaging chip, said method comprising:

accessing row N+1+M of said array, where M is a predetermined number of rows, whereby said method sets the image exposure time of said third row.

7. (Original) A method in accordance with claim 6, wherein said step of accessing said N+1+M row of said array occurs substantially simultaneously with said step of accessing said row N+1 of said array.

8. (Canceled)

9. (Canceled)

10. (Currently amended) A method in accordance with claim 8, In a semiconductor imaging chip having a plurality of active pixel sensors arranged in an array of rows and columns, whercin a current row of said array has an access line shared with a reset line of a previous row of said array to form a shared access/reset line which simultaneously accesses said current row and resets said previous row, a method for accessing the pixel signal values of said active pixel sensors, said method comprising:

accessing row N of said array a first time;

accessing row N+1 of said array, said row N of said array being the previous row to said row N+1 of said array;

accessing row N+1+ M of said array, where M is a predetermined number of rows; and thereafter;

accessing row N of said array a second time,

whereby said method sets the image exposure time of said row N+1+M; and

wherein said step of accessing said N+1+M row of said array occurs substantially simultaneously with said step of accessing said row N+1 of said array; and

wherein each active pixel sensor has a respective internal offset voltage output superimposed on its respective active pixel sensor output, and said method further includes canceling the respective internal offset voltage appearing at the output of a given active pixel sensor on said current row to form a corrected output, said method further comprising:

storing a first sample of said given active pixel sensor of row N of said array during said first time;

storing a second sample of said given active pixel sensor of row N of said array during said second time; and

subtracting said second sample from said first sample to form said corrected output from said given active pixel sensor.

11. (Cancelled)

12. (Cancelled)

13. (Cancelled)

14. (Cancelled)

15. (Cancelled)

16. (Cancelled)

17. (Cancelled)

18. (Cancelled)

19. (Cancelled)

20. (Cancelled)